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Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	66MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (1), 10/100Mbps (1)
SATA	-
USB	-
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 95°C (TA)
Security Features	-
Package / Case	357-BBGA
Supplier Device Package	357-PBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc855tczq66d4

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Overview

1 Overview

The MPC860 power quad integrated communications controller (PowerQUICCTM) is a versatile one-chip integrated microprocessor and peripheral combination designed for a variety of controller applications. It particularly excels in communications and networking systems. The PowerQUICC unit is referred to as the MPC860 in this hardware specification.

The MPC860 implements Power ArchitectureTM technology and contains a superset of Freescale's MC68360 quad integrated communications controller (QUICC), referred to here as the QUICC, RISC communications proceessor module (CPM). The CPU on the MPC860 is a 32-bit core built on Power Architecture technology that incorporates memory management units (MMUs) and instruction and data caches.. The CPM from the MC68360 QUICC has been enhanced by the addition of the inter-integrated controller (I²C) channel. The memory controller has been enhanced, enabling the MPC860 to support any type of memory, including high-performance memories and new types of DRAMs. A PCMCIA socket controller supports up to two sockets. A real-time clock has also been integrated.

Table 1 shows the functionality supported by the MPC860 family.

	Cache (Kbytes)	Ethe	ernet			Reference ¹	
Part	Instruction Cache	Data Cache	10T	10/100	ΑΤΜ	SCC		
MPC860DE	4	4	Up to 2	_	_	2	1	
MPC860DT	4	4	Up to 2	1	Yes	2	1	
MPC860DP	16	8	Up to 2	1	Yes	2	1	
MPC860EN	4	4	Up to 4	—	—	4	1	
MPC860SR	4	4	Up to 4	—	Yes	4	1	
MPC860T	4	4	Up to 4	1	Yes	4	1	
MPC860P	16	8	Up to 4	1	Yes	4	1	
MPC855T	4	4	1	1	Yes	1	2	

Table 1. MPC860 Family Functionality

Supporting documentation for these devices refers to the following:

1. MPC860 PowerQUICC Family User's Manual (MPC860UM, Rev. 3)

2. MPC855T User's Manual (MPC855TUM, Rev. 1)



2 Features

The following list summarizes the key MPC860 features:

- Embedded single-issue, 32-bit core (implementing the Power Architecture technology) with thirty-two 32-bit general-purpose registers (GPRs)
 - The core performs branch prediction with conditional prefetch without conditional execution.
 - 4- or 8-Kbyte data cache and 4- or 16-Kbyte instruction cache (see Table 1)
 - 16-Kbyte instruction caches are four-way, set-associative with 256 sets; 4-Kbyte instruction caches are two-way, set-associative with 128 sets.
 - 8-Kbyte data caches are two-way, set-associative with 256 sets; 4-Kbyte data caches are two-way, set-associative with 128 sets.
 - Cache coherency for both instruction and data caches is maintained on 128-bit (4-word) cache blocks.
 - Caches are physically addressed, implement a least recently used (LRU) replacement algorithm, and are lockable on a cache block basis.
 - MMUs with 32-entry TLB, fully-associative instruction, and data TLBs
 - MMUs support multiple page sizes of 4-, 16-, and 512-Kbytes, and 8-Mbytes; 16 virtual address spaces and 16 protection groups
 - Advanced on-chip-emulation debug mode
- Up to 32-bit data bus (dynamic bus sizing for 8, 16, and 32 bits)
- 32 address lines
- Operates at up to 80 MHz
- Memory controller (eight banks)
 - Contains complete dynamic RAM (DRAM) controller
 - Each bank can be a chip select or \overline{RAS} to support a DRAM bank.
 - Up to 15 wait states programmable per memory bank
 - Glueless interface to DRAM, SIMMS, SRAM, EPROM, Flash EPROM, and other memory devices
 - DRAM controller programmable to support most size and speed memory interfaces
 - Four $\overline{\text{CAS}}$ lines, four $\overline{\text{WE}}$ lines, and one $\overline{\text{OE}}$ line
 - Boot chip-select available at reset (options for 8-, 16-, or 32-bit memory)
 - Variable block sizes (32 Kbytes to 256 Mbytes)
 - Selectable write protection
 - On-chip bus arbitration logic
- General-purpose timers
 - Four 16-bit timers or two 32-bit timers
 - Gate mode can enable/disable counting
 - Interrupt can be masked on reference match and event capture.

MPC860 PowerQUICC Family Hardware Specifications, Rev. 10



Characteristic	Symbol	Min	Max	Unit
Input leakage current, V_{in} = 3.6 V (except TMS, TRST, DSCK, and DSDI pins)	l _{in}	—	10	μA
Input leakage current, V _{in} = 0 V (except TMS, TRST, DSCK, and DSDI pins)	l _{in}	—	10	μA
Input capacitance ²	C _{in}	—	20	pF
Output high voltage, $I_{OH} = -2.0$ mA, $V_{DDH} = 3.0$ V (except XTAL, XFC, and open-drain pins)	V _{OH}	2.4	—	V
$\label{eq:IDE_Interm} \begin{array}{ c c c c c } \hline Output low voltage \\ I_{OL} = 2.0 \text{ mA, CLKOUT} \\ I_{OL} = 3.2 \text{ mA}^3 \\ I_{OL} = 5.3 \text{ mA}^4 \\ I_{OL} = 7.0 \text{ mA, TXD1/PA14, TXD2/PA12} \\ I_{OL} = 8.9 \text{ mA, TS, TA, TEA, BI, BB, HRESET, SRESET} \end{array}$	V _{OL}		0.5	V

Table 6. DC Electrical Specifications (continued)

 1 V_{IL}(max) for the I²C interface is 0.8 V rather than the 1.5 V as specified in the I²C standard.

² Input capacitance is periodically sampled.

- ³ A(0:31), TSIZ0/REG, TSIZ1, D(0:31), DP(0:3)/IRQ(3:6), RD/WR, BURST, RSV/IRQ2, IP_B(0:1)/IWP(0:1)/VFLS(0:1), IP_B2/IOIS16_B/AT2, IP_B3/IWP2/VF2, IP_B4/LWP0/VF0, IP_B5/LWP1/VF1, IP_B6/DSDI/AT0, IP_B7/PTR/AT3, RXD1/PA15, RXD2/PA13, L1TXDB/PA11, L1RXDB/PA10, L1TXDA/PA9, L1RXDA/PA8, TIN1/L1RCLKA/BRGO1/CLK1/PA7, BRGCLK1/TOUT1/CLK2/PA6, TIN2/L1TCLKA/BRGO2/CLK3/PA5, TOUT2/CLK4/PA4, TIN3/BRGO3/CLK5/PA3, BRGCLK2/ L1RCLKB/TOUT3/CLK6/PA2, TIN4/BRGO4/CLK7/PA1, L1TCLKB/TOUT4/CLK8/PA0, REJCT1/SPISEL/PB31, SPICLK/ PB30,SPIMOSI/PB29, BRGO4/SPIMISO/PB28, BRGO1/I2CSDA/PB27, BRGO2/I2CSCL/PB26, SMTXD1/PB25, SMRXD1/ PB24, SMSYN1/SDACK1/PB23, SMSYN2/SDACK2/PB22, SMTXD2/L1CLKOB/PB21, SMRXD2/L1CLKOA/PB20, L1ST1/ RTS1/PB19, L1ST2/RTS2/PB18, L1ST3/L1RQB/PB17, L1ST4/L1RQA/PB16, BRGO3/PB15, RSTRT1/PB14, L1ST1/RTS1/ DREQ0/PC15, L1ST2/RTS2/DREQ1/PC14, L1ST3/L1RQB/PC13, L1ST4/L1RQA/PC12, CTS1/PC11, TGATE1/CD1/PC10, CTS2/PC9, TGATE2/CD2/PC8, SDACK2/L1TSYNCB/PC7, L1RSYNCB/PC6, SDACK1/L1TSYNCA/PC5, L1RSYNCA/PC4, PD15, PD14, PD13, PD12, PD11, PD10, PD9, PD8, PD5, PD6, PD7, PD4, PD3, MII_MDC, MII_TX_ER, MII_EN, MII_MDIO, and MII_TXD[0:3]
- ⁴ BDIP/GPL_B(5), BR, BG, FRZ/IRQ6, CS(0:5), CS(6)/CE(1)_B, CS(7)/CE(2)_B, WE0/BS_B0/IORD, WE1/BS_B1/IOWR, WE2/BS_B2/PCOE, WE3/BS_B3/PCWE, BS_A(0:3), GPL_A0/GPL_B0, OE/GPL_A1/GPL_B1, GPL_A(2:3)/GPL_B(2:3)/ CS(2:3), UPWAITA/GPL_A4, UPWAITB/GPL_B4, GPL_A5, ALE_A, CE1_A, CE2_A, ALE_B/DSCK/AT1, OP(0:1), OP2/MODCK1/STS, OP3/MODCK2/DSDO, and BADDR(28:30)



Layout Practices

where:

 Ψ_{JT} = thermal characterization parameter

 T_T = thermocouple temperature on top of package

 P_D = power dissipation in package

The thermal characterization parameter is measured per JEDEC JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

7.6 References

Semiconductor Equipment and Materials International	(415) 964-5111
805 East Middlefield Rd.	
Mountain View, CA 94043	
MIL-SPEC and EIA/JESD (JEDEC) Specifications	800-854-7179 or
(Available from Global Engineering Documents)	303-397-7956
JEDEC Specifications	http://www.jedec.org

- 1. C.E. Triplett and B. Joiner, "An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module," Proceedings of SemiTherm, San Diego, 1998, pp. 47–54.
- B. Joiner and V. Adams, "Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling," Proceedings of SemiTherm, San Diego, 1999, pp. 212–220.

8 Layout Practices

Each V_{DD} pin on the MPC860 should be provided with a low-impedance path to the board's supply. Each GND pin should likewise be provided with a low-impedance path to ground. The power supply pins drive distinct groups of logic on the chip. The V_{DD} power supply should be bypassed to ground using at least four 0.1 µF-bypass capacitors located as close as possible to the four sides of the package. The capacitor leads and associated printed circuit traces connecting to chip V_{DD} and GND should be kept to less than half an inch per capacitor lead. A four-layer board employing two inner layers as V_{CC} and GND planes is recommended.

All output pins on the MPC860 have fast rise and fall times. Printed circuit (PC) trace interconnection length should be minimized in order to minimize undershoot and reflections caused by these fast output switching times. This recommendation particularly applies to the address and data buses. Maximum PC trace lengths of 6 inches are recommended. Capacitance calculations should consider all device loads as well as parasitic capacitances due to the PC traces. Attention to proper PCB layout and bypassing becomes especially critical in systems with higher capacitive loads because these loads create higher transient currents in the V_{CC} and GND circuits. Pull up all unused inputs or signals that will be inputs during reset. Special care should be taken to minimize the noise levels on the PLL supply pins.



		33	MHz	40 1	MHz	50 I	MHz	66 I	ИНz	
Num	Characteristic	Min	Мах	Min	Мах	Min	Мах	Min	Max	Unit
B29d	\overline{WE} (0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 0	43.45		35.5	_	28.00		20.73	_	ns
B29e	$\overline{\text{CS}}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	43.45		35.5		28.00		29.73	_	ns
B29f	\overline{WE} (0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, EBDF = 1	8.86	_	6.88	_	5.00	_	3.18		ns
B29g	$\overline{\text{CS}}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	8.86	_	6.88	—	5.00	—	3.18	_	ns
B29h	$\overline{WE}(0:3)$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 1	38.67	—	31.38	—	24.50	—	17.83	_	ns
B29i	$\overline{\text{CS}}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	38.67		31.38		24.50		17.83	_	ns
B30	\overline{CS} , \overline{WE} (0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access ⁸	5.58	—	4.25	—	3.00	—	1.79		ns
B30a	$\overline{\text{WE}}(0:3)$ negated to A(0:31), BADDR(28:30) invalid GPCM, write access, TRLX = 0, CSNT = 1, $\overline{\text{CS}}$ negated to A(0:31) invalid GPCM write access, TRLX = 0, CSNT = 1 ACS = 10, or ACS = 11, EBDF = 0	13.15	_	10.50	_	8.00	_	5.58		ns
B30b	$\label{eq:weighted} \hline WE(0:3) \ negated to \ A(0:31), \ invalid \ GPCM \\ BADDR(28:30) \ invalid \ GPCM \ write \ access, \\ TRLX = 1, \ CSNT = 1. \ \overline{CS} \ negated to \\ A(0:31), \ Invalid \ GPCM, \ write \ access, \\ TRLX = 1, \ CSNT = 1, \ ACS = 10, \ or \\ ACS = 11, \ EBDF = 0 \\ \hline \hline \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$	43.45	_	35.50	_	28.00	_	20.73	_	ns
B30c	$\label{eq:weighted} \begin{array}{ c c c c } \hline WE(0:3) \mbox{ negated to } A(0:31), \mbox{ BADDR}(28:30) \\ \hline \mbox{ invalid GPCM write access, TRLX = 0, } \\ \hline CSNT = 1. \end{cmathcelline CS} \mbox{ negated to } A(0:31) \mbox{ invalid GPCM write access, TRLX = 0, } \\ \hline GPCM \mbox{ write access, TRLX = 0, } \\ \hline ACS = 10, \mbox{ ACS = 11, EBDF = 1} \end{array}$	8.36	_	6.38	_	4.50	_	2.68		ns
B30d	$\overline{WE}(0:3)$ negated to A(0:31), BADDR(28:30) invalid GPCM write access, TRLX = 1, CSNT =1. \overline{CS} negated to A(0:31) invalid GPCM write access TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	38.67	_	31.38	_	24.50	_	17.83		ns
B31	CLKOUT falling edge to CS valid—as requested by control bit CST4 in the corresponding word in UPM	1.50	6.00	1.50	6.00	1.50	6.00	1.50	6.00	ns

Table 7. Bus Operation Timings (continued)



Figure 5 provides the timing for the synchronous output signals.



Figure 5. Synchronous Output Signals Timing

Figure 6 provides the timing for the synchronous active pull-up and open-drain output signals.



Figure 6. Synchronous Active Pull-Up Resistor and Open-Drain Outputs Signals Timing





Figure 15. External Bus Write Timing (GPCM Controlled—TRLX = 0 or 1, CSNT = 1)







Figure 17. External Bus Timing (UPM Controlled Signals)



Figure 18 provides the timing for the asynchronous asserted UPWAIT signal controlled by the UPM.



Figure 18. Asynchronous UPWAIT Asserted Detection in UPM Handled Cycles Timing

Figure 19 provides the timing for the asynchronous negated UPWAIT signal controlled by the UPM.



Figure 19. Asynchronous UPWAIT Negated Detection in UPM Handled Cycles Timing





Figure 20 provides the timing for the synchronous external master access controlled by the GPCM.

Figure 20. Synchronous External Master Access Timing (GPCM Handled ACS = 00)

Figure 21 provides the timing for the asynchronous external master memory access controlled by the GPCM.





Figure 22 provides the timing for the asynchronous external master control signals negation.



Figure 22. Asynchronous External Master—Control Signals Negation Timing



Table 9 shows the PCMCIA timing for the MPC860.

Table 9. PCMCIA Timing

Num	Obevectovictic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
Num	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Unit
P44	A(0:31), REG valid to PCMCIA Strobe asserted ¹	20.73	—	16.75	—	13.00	—	9.36	—	ns
P45	A(0:31), $\overline{\text{REG}}$ valid to ALE negation ¹	28.30	—	23.00	—	18.00	—	13.15	_	ns
P46	CLKOUT to REG valid	7.58	15.58	6.25	14.25	5.00	13.00	3.79	11.84	ns
P47	CLKOUT to REG invalid	8.58	—	7.25	—	6.00	—	4.84	_	ns
P48	CLKOUT to $\overline{CE1}$, $\overline{CE2}$ asserted	7.58	15.58	6.25	14.25	5.00	13.00	3.79	11.84	ns
P49	CLKOUT to $\overline{CE1}$, $\overline{CE2}$ negated	7.58	15.58	6.25	14.25	5.00	13.00	3.79	11.84	ns
P50	CLKOUT to PCOE, IORD, PCWE, IOWR assert time	—	11.00		11.00	—	11.00	—	11.00	ns
P51	CLKOUT to PCOE, IORD, PCWE, IOWR negate time	2.00	11.00	2.00	11.00	2.00	11.00	2.00	11.00	ns
P52	CLKOUT to ALE assert time	7.58	15.58	6.25	14.25	5.00	13.00	3.79	10.04	ns
P53	CLKOUT to ALE negate time	—	15.58		14.25	_	13.00	—	11.84	ns
P54	PCWE, IOWR negated to D(0:31) invalid ¹	5.58	—	4.25	—	3.00	—	1.79	_	ns
P55	WAITA and WAITB valid to CLKOUT rising edge ¹	8.00	—	8.00	—	8.00	—	8.00	—	ns
P56	CLKOUT rising edge to WAITA and WAITB invalid ¹	2.00	—	2.00	—	2.00	—	2.00	—	ns

¹ PSST = 1. Otherwise add PSST times cycle time.

PSHT = 0. Otherwise add PSHT times cycle time.

These synchronous timings define when the WAITx signals are detected in order to freeze (or relieve) the PCMCIA current cycle. The WAITx assertion will be effective only if it is detected 2 cycles before the PSL timer expiration. See Chapter 16, "PCMCIA Interface," in the *MPC860 PowerQUICCTM Family User's Manual*.





Figure 25 provides the PCMCIA access cycle timing for the external bus read.

Figure 25. PCMCIA Access Cycle Timing External Bus Read



Table 10 shows the PCMCIA port timing for the MPC860.

Table 10. PCMCIA Port Timing

Num	Charactoristic	33	MHz	40 MHz		50 MHz		66 MHz		Unit
Num	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Unit
P57	CLKOUT to OPx valid	—	19.00	—	19.00	_	19.00	_	19.00	ns
P58	HRESET negated to OPx drive ¹	25.73	—	21.75	—	18.00	—	14.36	—	ns
P59	IP_Xx valid to CLKOUT rising edge	5.00	—	5.00	—	5.00	—	5.00	—	ns
P60	CLKOUT rising edge to IP_Xx invalid	1.00	—	1.00	—	1.00	—	1.00	—	ns

¹ OP2 and OP3 only.

Figure 28 provides the PCMCIA output port timing for the MPC860.



Figure 28. PCMCIA Output Port Timing

Figure 29 provides the PCMCIA output port timing for the MPC860.



Figure 29. PCMCIA Input Port Timing



Table 12 shows the reset timing for the MPC860.

Table 12. Reset Timing

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		llmit
Num	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Unit
R69	CLKOUT to HRESET high impedance	—	20.00	—	20.00	—	20.00	—	20.00	ns
R70	CLKOUT to SRESET high impedance	—	20.00	—	20.00	—	20.00	—	20.00	ns
R71	RSTCONF pulse width	515.15	—	425.00		340.00	—	257.58	—	ns
R72	_	_	—	—	—	—	—	—	—	
R73	Configuration data to HRESET rising edge setup time	504.55	—	425.00	—	350.00	—	277.27	—	ns
R74	Configuration data to RSTCONF rising edge setup time	350.00	_	350.00	_	350.00	_	350.00	_	ns
R75	Configuration data hold time after RSTCONF negation	0.00	—	0.00	—	0.00	—	0.00	—	ns
R76	Configuration data hold time after HRESET negation	0.00	—	0.00	—	0.00	—	0.00	—	ns
R77	HRESET and RSTCONF asserted to data out drive	_	25.00		25.00	_	25.00	_	25.00	ns
R78	RSTCONF negated to data out high impedance	-	25.00	—	25.00	—	25.00	—	25.00	ns
R79	CLKOUT of last rising edge before chip three-state HRESET to data out high impedance	_	25.00	—	25.00	—	25.00	—	25.00	ns
R80	DSDI, DSCK setup	90.91	—	75.00	—	60.00	—	45.45	—	ns
R81	DSDI, DSCK hold time	0.00	—	0.00	—	0.00	—	0.00	—	ns
R82	SRESET negated to CLKOUT rising edge for DSDI and DSCK sample	242.42		200.00		160.00		121.21		ns



IEEE 1149.1 Electrical Specifications



Figure 35. JTAG Test Clock Input Timing



Figure 36. JTAG Test Access Port Timing Diagram



Figure 37. JTAG TRST Timing Diagram



MPC860 PowerQUICC Family Hardware Specifications, Rev. 10





Figure 42. PIP TX (Pulse Mode) Timing Diagram

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11.4 Baud Rate Generator AC Electrical Specifications

Table 17 provides the baud rate generator timings as shown in Figure 49.

Table 17. Baud Rate Generator Timing

Num	Charactariatia	All Freq	Unit	
Nulli	Characteristic	Min	Max 10 60 —	Unit
50	BRGO rise and fall time	—	10	ns
51	BRGO duty cycle	40	60	%
52	BRGO cycle	40	—	ns



Figure 49. Baud Rate Generator Timing Diagram

11.5 Timer AC Electrical Specifications

Table 18 provides the general-purpose timer timings as shown in Figure 50.

Table 18. Timer Timing

Num	Characteristic	All Freq	Unit	
Num	Characteristic	Min	Мах	Unit
61	TIN/TGATE rise and fall time	10	—	ns
62	TIN/TGATE low time	1	—	CLK
63	TIN/TGATE high time	2	—	CLK
64	TIN/TGATE cycle time	3	—	CLK
65	CLKO low to TOUT valid	3	25	ns









11.12 I²C AC Electrical Specifications

Table 26 provides the I^2C (SCL < 100 kHz) timings.

Table 26. I²C Timing (SCL < 100 kHz)

Num	Characteristic	All Freq	uencies	Unit
Nulli		Min	Мах	Unit
200	SCL clock frequency (slave)	0	100	kHz
200	SCL clock frequency (master) ¹	1.5	100	kHz
202	Bus free time between transmissions	4.7	—	μS
203	Low period of SCL	4.7	—	μS
204	High period of SCL	4.0	—	μS
205	Start condition setup time	4.7	—	μS
206	Start condition hold time	4.0	—	μS
207	Data hold time	0	—	μS
208	Data setup time	250	—	ns
209	SDL/SCL rise time	—	1	μS
210	SDL/SCL fall time	—	300	ns
211	Stop condition setup time	4.7	—	μS

SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3 × pre_scaler × 2). The ratio SYNCCLK/(BRGCLK/pre_scaler) must be greater than or equal to 4/1.

Table 27 provides the I^2C (SCL > 100 kHz) timings.

Table 27. . I²C Timing (SCL > 100 kHz)

Num	Characteristic	Expression	All Freq	Unit	
Num	Characteristic	Expression	Min	Мах	Unit
200	SCL clock frequency (slave)	fSCL	0	BRGCLK/48	Hz
200	SCL clock frequency (master) ¹	fSCL	BRGCLK/16512	BRGCLK/48	Hz
202	Bus free time between transmissions		1/(2.2 * fSCL)	—	S
203	Low period of SCL		1/(2.2 * fSCL)	—	S
204	High period of SCL		1/(2.2 * fSCL)	_	S
205	Start condition setup time		1/(2.2 * fSCL)	—	S
206	Start condition hold time		1/(2.2 * fSCL)	—	S
207	Data hold time		0	_	S
208	Data setup time		1/(40 * fSCL)	—	S
209	SDL/SCL rise time		—	1/(10 * fSCL)	S
210	SDL/SCL fall time		—	1/(33 * fSCL)	S
211	Stop condition setup time		1/2(2.2 * fSCL)	—	s

SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3) × pre_scaler × 2). The ratio SYNCCLK/(BRGCLK / pre_scaler) must be greater than or equal to 4/1.

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Figure 78 shows the mechanical dimensions of the ZQ PBGA package.



- 1. All Dimensions in millimeters.
- 2. Dimensions and tolerance per ASME Y14.5M, 1994.
- 3. Maximum Solder Ball Diameter measured parallel to Datum A.
- 4. Datum A, the seating plane, is defined by the spherical crowns of the solder balls.

Figure 78. Mechanical Dimensions and Bottom Surface Nomenclature of the ZQ PBGA Package